

**IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE**

Appl. No. :
Applicant(s) : DE JONG et al.
Filed : Herewith
TC/A.U. : 2857 (in parent)
Examiner : Craig MILLER (in parent)
Atty. Docket : N-17203-A

Title: CIRCUIT WITH INTERCONNECT TEST UNIT AND
A METHOD OF TESTING INTERCONNECTS
BETWEEN A FIRST AND A SECOND
ELECTRONIC CIRCUIT

PRELIMINARY AMENDMENT

Mail Stop **Non-Fee Amendment**
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Preliminary to examination of the above-referenced application, please amend
the application as follows.

This paper includes (each beginning on a separate sheet):

- 1. Amendments to the specification;**
- 2. Amendments to the claims; and**
- 3. Remarks/Discussion of issues.**